L Number	Hits	Search Text	DB	Time stamp
1	792	(test$3 with (integrated adj3 circuit)) same (test adj5 board)	USPAT; US-PGPUB; EPO; JPO; DEPWENT; IBM_TDB	2003/02/26 16:12
2	2	((digital near "5" analog) with (convering adj4 circuit))	USPAT; US-PGPUB; EPO; JPO; DEPWENT; IBM_TDB	2003/02/26 16:14
3	1	((digital near5 analog) with (convering adj4 circuit))	USPAT; US-PGPUB; EPO; JPO; DEPWENT; IBM_TDB	2003/02/26 16:19
4	1143	((digital adj5 analog) with (converting adj4 circuit))	USPAT; US-PGPUB; EPO; JPO; DEPWENT; IBM_TDB	2003/02/26 16:20
5	0	((test$3 with (integrated adj3 circuit)) same (test adj5 board)) and (((digital adj5 analog) with (converting adj4 circuit)))	USPAT; US-PGPUB; EPO; JPO; DEPWENT; IBM_TDB	2003/02/26 16:20
6	3	(((digital adj5 analog) with (converting adj4 circuit))) and (test with board)	USPAT; US-PGPUB; EPO; JPO; DEPWENT; IBM_TDB	2003/02/26 16:22
7	3	(((digital adj5 analog) with (converting adj4 circuit))) and (test and DUT)	USPAT; US-PGPUB; EPO; JPO; DEPWENT; IBM_TDB	2003/02/26 16:22
8	91	(((digital adj5 analog) with (converting adj4 circuit))) and test	USPAT; US-PGPUB; EPO; JPO; DEPWENT; IBM_TDB	2003/02/26 16:24
9	23419	testing and semiconductor and integrated and circuit	USPAT; US-PGPUB; EPO; JPO; DEPWENT; IBM_TDB	2003/02/26 16:25
10	243243	analog and digital and convert$4	USPAT; US-PGPUB; EPO; JPO; DEPWENT; IBM_TDB	2003/02/26 16:27
11	30458	test and board and memory	USPAT; US-PGPUB; EPO; JPO; DEPWENT; IBM_TDB	2003/02/26 16:28
12	1537	(testing and semiconductor and integrated and circuit) and (analog and digital and convert$4) and (test and board and memory)	USPAT; US-PGPUB; EPO; JPO; DEPWENT; IBM_TDB	2003/02/26 16:29
13	167	324/716.ccls.	USPAT; US-PGPUB; EPO; JPO; DEPWENT; IBM_TDB	2003/02/26 16:29

C:\APPS\east\workspaces\917959.wsp

14	104293	324/$.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/26 16:29
15	36591	714/$.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/26 16:30
16	125	((testing and semiconductor and integrated and circuit) and (analog and digital and convert$4) and (test and board and memory)) and 324/$.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/26 16:43
17	141	((testing and semiconductor and integrated and circuit) and (analog and digital and convert$4) and (test and board and memory)) and 714/$.ccls.	USPAT; US-PGPUB; EPO; JPO; DERWENT; IBM_TDB	2003/02/26 16:43